



Sheet 1 of 8

Form PTO-1449 (REV. 1/06)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 124086.03		APPLICATION NO. New U.S. Patent Application 10/775326	
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)				APPLICANT(S) Hiroyuki NAGASAKA et al.			
				FILING DATE August 11, 2006		ORGRP 2051 1795	

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BR	4	2004/0169924 A1	09-02-2004	FLAGELLO ET AL.
BR	5	2004/0180294 A1	09-16-2004	BABA-ALI ET AL.
BR	6	2004/0180299 A1	09-16-2004	ROLLANO ET AL.
BR	7	2004/0224265 A1	11-11-2004	ENDO ET AL.
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BR	12	WO 2005/054955 A2	06-16-2005	WIPO	X	X
BR	13	WO 02/091078 A1	11-14-2002	WIPO	X	X
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INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)				APPLICANT(S) Hiroyuki NAGASAKA et al.			
				FILING DATE August 11, 2006		GROUP 2891 1795	
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BR	30	WO 2004/092833 A2	10-28-2004	WIPO	X	X	
BR	31	WO 2004/093130 A2	10-28-2004	WIPO	X	X	
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INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)				APPLICANT(S) Hiroyuki NAGASAKA et al.			
				FILING DATE August 11, 2006		GROUP 384 1795	
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				FILING DATE August 11, 2006		GROUP 885+ 1795	
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INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)				APPLICANT(S) Hiroyuki NAGASAKA et al.			
				FILING DATE August 11, 2006		GROUP 3854 1795	
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BR	93	WO99/49504	9/30/1999	WIPO	X	X	
BR	94	JP A 62-65326	3/24/1987	JAPAN	X	X	
BR	95	JP A 63-157419	6/30/1988	JAPAN	X	X	
BR	96	JP A 5-304072	11/16/1993	JAPAN	X	X	
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				FILING DATE August 11, 2006		GROUP 2864 1795	
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	111	JP A 10-154659	6/9/1998	JAPAN	X	X	
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				FILING DATE August 11, 2006		GROUP 1795 2851 1356	

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Client Ref.

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**INFORMATION DISCLOSURE STATEMENT
BY APPLICANT**

Applicant: DIERICHS et al.

Appln. No.: 10/775,326

Filing Date: February 11, 2004

Date: September 27, 2007

Page

1

of

4

Examiner: Brittany L. Raymond Group Art Unit: 1756/1795

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BR	CC	Office Action dated August 17, 2006 issued for U.S. Appln. No. 10/898,674			

Examiner: *Brittany L. Raymond*

Date Considered: 10/9/2007

*EXAMINER: Initial citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include a copy of this form with next communication to Applicant.

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INFORMATION DISCLOSURE STATEMENT BY APPLICANT

Applicant: DIERICHS

Appln. No.: 10/775,326

Filing Date: February 11, 2004

Date: September 27, 2007

Page

2

of

4

Examiner: Brittany L. Raymond Group Art Unit: 1758 1795

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Examiner *Brittany Raymond*

Date Considered: 10/9/2007

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FORM PTO-1449 (modified)
To: U.S. Department of Commerce
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Atty. Dkt. No.	M#	Client Ref.
081468	0308270	P-1812.000-US

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

Applicant: DIERICHS

Appln. No.: 10/775,326

Filing Date: February 11, 2004

Date: September 27, 2007

Page

3

of 4

Examiner: Brittany L. Raymond

Group Art Unit: 4756-1795

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						Enclosed	No	Enclose	No
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4

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	SSSSR					
	TTTTT					
	UUUUR					

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						Enclosed	No	Enclose	No
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	WWWW								
	XXXXR								
	YYYYR								
	ZZZR								
	AAAAA								
	BBBBB								
	CCCCC								
	DDDDD								
	EEEEEE								
	FFFFFF								
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